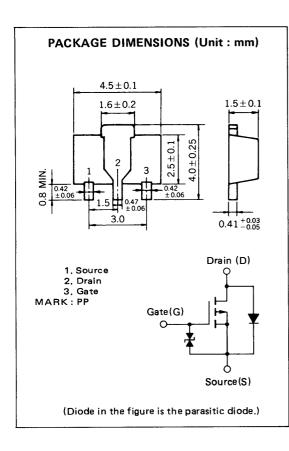
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P1 98.2



MOS FIELD EFFECT TRANSISTOR **2SJ213**

P-CHANNEL MOS FET FOR SWITCHING



The 2SJ213, P-channel vertical type MOS FET, is a switching device which can be driven directly by the output of ICs having a 5 V power source.

As the MOS FET has low on-state resistance and excellent switching characteristics, it is suitable for driving actuators such as motors, relays, and solenoids.

FEATURES

- Directly driven by ICs having a 5 V power supply.
- Has low on-state resistance

$$R_{DS(on)}$$
 = 5.0 Ω MAX. @V_{GS} = -4.0 V, I_D = -0.3 A $R_{DS(on)}$ = 4.2 Ω MAX. @V_{GS} = -10 V, I_D = -0.3 A

QUALITY GRADE

Standard

Please refer to "Quality grade on NEC Semiconductor Devices" (Document number IEI-1209) published by NEC Corporation to know the specification of quality grade on the devices and its recommended applications.

ABSOLUTE MAXIMUM RATINGS ($T_a = 25$ °C)

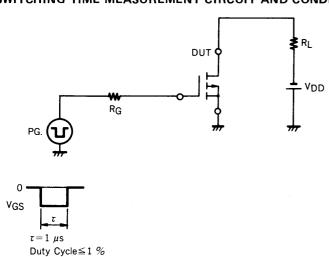
PARAMETER	SYMBOL	RATINGS	UNIT	TEST CONDITIONS
Drain to Source Voltage	VDSS	-100	V	V _{GS} = 0
Gate to Source Voltage	V _{GSS}	∓20	V	V _{DS} = 0
Drain Current	I _D (DC)	∓500	mA	
Drain Current	¹ D(pulse)	∓1.0	Α	PW \leq 10 ms, Duty Cycle \leq 50 %
Total Power Dissipation	PT	2,0	w	when using ceramic board of 16 cm ² x 0.7 mm
Channel Temperature	T _{ch}	150	°C	
Storage Temperature	T _{stg}	-55 to +150	°C	

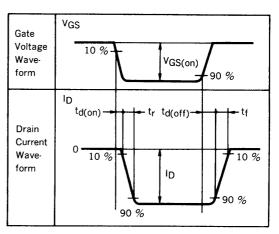


ELECTRICAL CHARACTERISTICS (T_a = 25 °C)

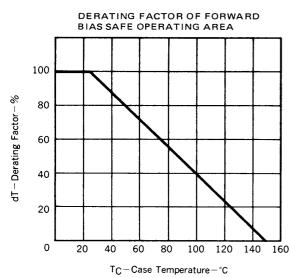
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	TEST CONDITIONS	
Drain Breaking Current	IDSS			-10	μА	V _{DS} = -100 V, V _{GS} = 0	
Gate Leakage Current	IGSS			∓10	μΑ	V _{GS} = ∓20 V, V _{DS} = 0	
Gate Cutoff Voltage	VGS(off)	-1.0	-2.1	-3.0	V	V _{DS} = -10 V, I _D = -1 mA	
Forward Transfer Admittance	lyfsl	0.4	0,5		s	V _{DS} = -5.0 V, I _D = -300 mA	
Drain to Source On-State Resistance 1	R _{DS} (on)1		2,5	5.0	Ω	V _{GS} = -4.0 V, I _D = -300 mA	
Drain to Source On-State Resistance 2	R _{DS} (on)2		1.8	4,2	Ω	V _{GS} = -10 V, I _D = -300 mA	
Input Capacitance	Ciss		165		pF		
Output Capacitance	Coss		75		pF	V _{DS} = -10 V, V _{GS} = 0, f = 1 MHz	
Feedback Capacitance	C _{rss}		13		pF		
On-State Delay Time	^t d(on)		110		ns		
Rise Time	t _r		320		ns	$I_D = -0.3 \text{ A}, R_L = 1.5 \Omega$	
Off-State Delay Time	^t d(off)		100		ns	- V _{GS(on)} = -4 V R _G = 10 Ω, V _{DD} = -5 V	
Fall Time	tf		130		ns	1 .	

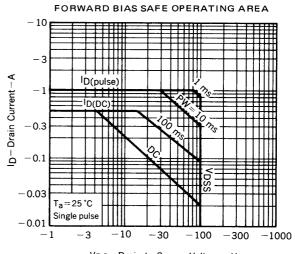
SWITCHING TIME MEASUREMENT CIRCUIT AND CONDITIONS

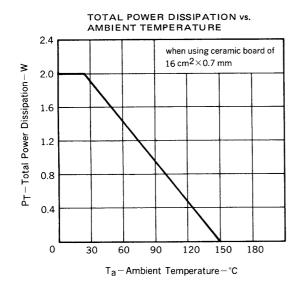


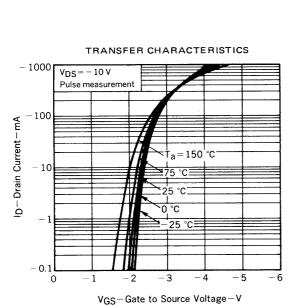


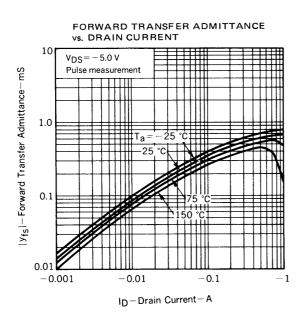
TYPICAL CHARACTERISTICS (T_a = 25 °C)

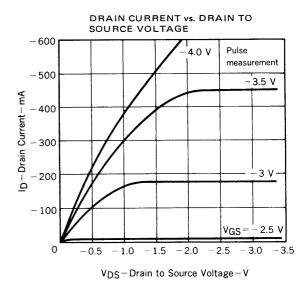


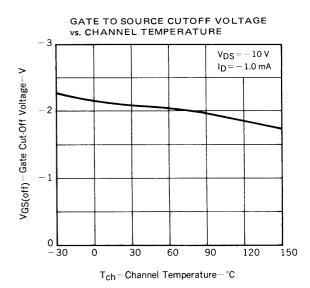


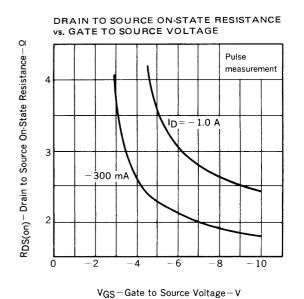




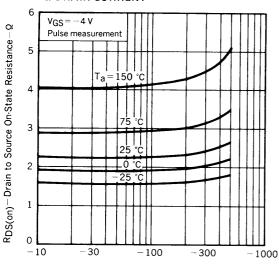




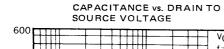


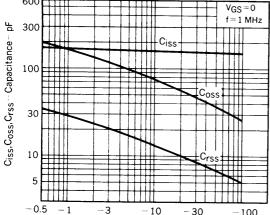


DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



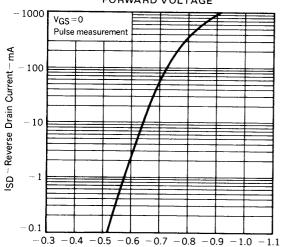
ID-Drain Current-mA





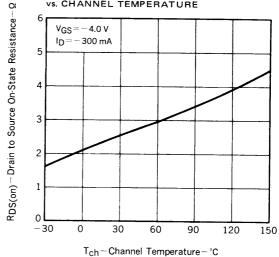
VDS - Drain to Source Voltage - V

SOURCE TO DRAIN DIODE FORWARD VOLTAGE

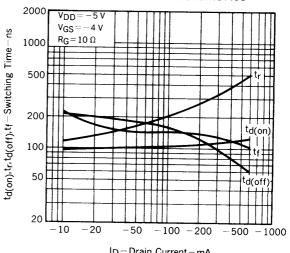


VSD-Source to Drain Voltage-V

DRAIN TO SOURCE ON-STATE RESISTANCE VS. CHANNEL TEMPERATURE



SWITCHING CHARACTERISTICS



ID-Drain Current-mA



RECOMMENDED SOLDERING CONDITIONS

Mounting of this product by soldering should be done under the following conditions. Please consult our representatives about soldering methods and conditions other than these.

SURFACE MOUNT TYPE

For details of the recommended soldering conditions, see the information document.

"Device Mounting Manual for Surface Mounting (IEI-1207)."

Soldering Method	Soldering Conditions	Symbol for Recommended Conditions	
Infrared Reflow	Package peak temp.: 230 °C Soldering time: within 30 sec (above 210 °C) Soldering times: 1, Days limitation: none*	IR30-00	
Vapor Phase Soldering	Package peak temp.: 215 °C Soldering time: within 40 sec (above 200 °C) Soldering times: 1, Days limitation: none*	VP15-00	
Wave Soldering	Soldering bath temp.: below 260 °C Soldering time: within 10 sec Soldering times: 1, Days limitation: none*	WS60-00	

^{*:} Stored days under storage conditions at 25 °C and below 65 % R.H. after the dry-pack has been opened.

Note 1: Combination of soldering methods should be avoided.

REFERENCE

Document Name	Document No.	
NEC semiconductor device reliability/quality control system.	TEI-1202	
Quality grade on NEC semiconductor devices.	IEI-1209	
Semiconductor device mounting technology manual.	IEI-1207	
Semiconductor device package manual.	IEI-1213	
Guide to quality assurance for semiconductor devices.	MEI-1202	
Semiconductor selection guide.	MF-1134	

(MEMO)

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Application examples recommended by NEC Corporation

Standard: Computer, Office equipment, Communication equipment, Test and Measurement equipment, Machine tools, Industrial robots, Audio and Visual equipment, Other consumer products, etc.

Special: Automotive and Transportation equipment, Traffic control systems, Antidisaster systems, Anticrime systems, etc.

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